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A BAYESIAN RELIABILITY GROWTH MODEL

by

Stephen M. Pollock

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ABSTRACT:

A model is presented for the reliability growth of a system during a test program. Parameters of the model are assumed to be random variables with appropriate prior density functions. Expressions are then derived that enable estimates (in the form of expectations) and precision statements (in the form of variances) to be made of

- . projected system reliability at time τ after the start of the test program
- . system reliability after the observation of failure data

Numerical examples are presented, and extension to multi-mode failures is mentioned.

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1. INTRODUCTION

1.1 RELIABILITY GROWTH

We are concerned with analyzing a particular model of reliability growth. The "growth" occurs in the following way: a system has some given value of a measure of reliability at the beginning of a length of time (i.e., at the start of a test period), and at the end of this period the value of this measure has changed -- hopefully, it will be improved.

This change may be caused by a number of factors. We shall be concerned, however, with only those factors that are the result of a conscious effort on the part of an interested observer (the "experimenter"). This effort is an attempt to improve or correct the system by some physical manipulation (such as component replacement or adjustment) or perhaps even by possible design change. The model considered below is similar to many discussed previously in the literature in that the corrections are attempted only after system failures have been observed.

A comparison between the model considered here (and its implications) with those contained in the literature is postponed until the final sections, where the differences in approach should become more apparent.

At this point we shall only mention the sort of information that should be, in the least, the content of any analysis of reliability growth. This content falls into two categories: inference and projection. In particular, an analysis should be able to produce statements (by necessity, probabilistic ones), on the basis of the model and the failure history to date, related to:

Inference: the present value of the reliability

Projection: the reliability at some future time, with or without continued application of the correction ("growth") process.

In order to make such statements, we shall first discuss two basic models which allow only a single failure mode for both discretely and continuously failing systems. This condition will be relaxed in a later section dealing with systems having many failure modes.

A final comment about the use of the word "system". As used in this paper, it shall mean simply a piece of equipment that has an assigned task to perform. If it does not perform it, it is said to have "failed". The system can be very simple, containing perhaps only one component. Or it can be extremely complicated. The only characteristic we shall use to distinguish between those degrees of complexity is the number of different (identifiable) ways it can stop functioning: i.e., the number of failure modes.

1.2 NOTATION

The following notation will be used in the description and analysis of the model discussed above:

.Capital letters stand for events or states of nature.

.An underlined variable, e.g., \underline{x} , is a random variable.

. $f_{\underline{x}}(x)$ = p.d.f. of the r.v $\underline{x} \equiv \lim_{\Delta x \rightarrow 0} \frac{\text{prob. } \{x \leq \underline{x} \leq x + \Delta x\}}{\Delta x}$

. $\delta(x)$ = Dirac delta function* of x .

*Defined most conveniently as the limit: $\delta(x) = \lim_{\epsilon \rightarrow 0} [h(x, \epsilon)]$ where

$$h(x, \epsilon) = \begin{cases} \frac{1}{\epsilon} & 0 \leq x \leq \epsilon \\ 0 & \text{otherwise} \end{cases}$$

. $P(A|B)$ = prob. {event A given event B has occurred}.

. $f_{\underline{x}}(x|A)$ = p.d.f. of \underline{x} given A has occurred.

$$\equiv \lim_{\Delta x \rightarrow 0} \frac{\text{prob. } \{x \leq \underline{x} \leq x + dx | A\}}{\Delta x}$$

. $E(\underline{x}|A) = \int x f_{\underline{x}}(x|A) dx$ = conditional expectation of \underline{x} given A.

. $V(\underline{x}|A) = \int [x - E(\underline{x}|A)]^2 f_{\underline{x}}(x|A) dx$ = conditional variance of \underline{x} given A.

. The letter H will be used to denote the event (state of nature) "historical experience": all the prior knowledge that is available concerning the model, values of parameters of the model, etc. Probabilities and p.d.f.'s conditioned only upon H are called "a priori", or "prior".

. A vector is noted by an arrow over it, with the vector dimension being indicated in parentheses, e.g., $\vec{t}(n) = (t_1, t_2, t_3, \dots, t_n)$.

2. THE CONTINUOUS MODEL

2.1 DESCRIPTION

The system has a single failure mode, and the time between failures, \underline{t} , is a random variable (r.v.) with probability density function (p.d.f.)

$$f_{\underline{t}}(t) = re^{-rt} \quad 0 \leq t \leq \infty.$$

The parameter r is commonly called the failure rate of the system (or, more properly, of the particular mode of failure). Since all relevant measures of reliability for an exponentially failing system can be obtained from the failure rate, it will be sufficient to concentrate upon its characteristics

only. The exponential function is not as restrictive as it may seem at first. Although it is certainly a simplistic assumption to make about complex systems, it becomes more valid as the systems become more elementary and serve to comprise the components of an even greater system. In addition, a conceptually simple (but laborious) extension of all the results of this paper is possible when it is postulated that r is in fact a function of time since last failure.

The system is, at any time, in one of two possible states (again, with respect to a single failure mode):

U = Unrepaired State

R = Repaired State

The numerical value of the failure rate r depends upon which state the system is in:

If the system is in the unrepaired state U, then $r = \lambda$;

If the system is in the repaired state R, then $r = \mu$.

The numbers λ and μ can be any non-negative values, and in fact μ is often zero. On the other hand, the value of μ might not be zero. Thus, although the system is said to be "repaired", it might still exhibit failures, albeit the failure rate when repaired might be quite low.

By virtue of a test program, the system changes states in the following restrictive way. After every failure, if the system is in U it 1) goes to R with probability a (the "repair probability"); or 2) remains in U with probability $(1-a)$. If the system is in R, it remains in R with probability one.

Thus, there can be only one transition to state R; once the system is repaired, it remains so.

This repair attempt happens instantaneously, after which the system operates until the time of the next failure (this time being again a random variable with failure rate depending upon whether the system has been put into state R or has remained in state U).

The model may be represented by a two-state Markov process, as shown by the flow diagram of Figure 1. The times between the transitions indicated in the diagram are the times between failures and, thus, are controlled by the failure rate of whichever state the system is in:

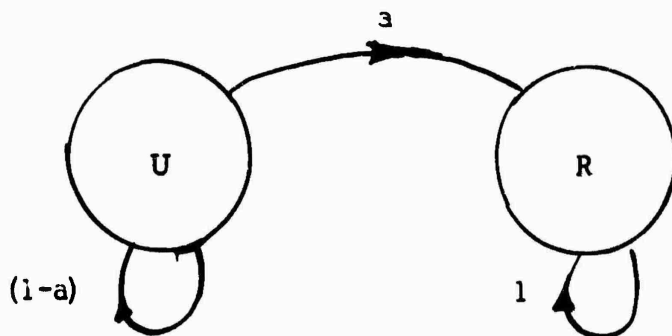


FIGURE 1

Flow diagram representation of growth model

U = Unrepaired state (failure rate = λ)

R = Repaired state (failure rate = μ)

a = repair probability

Which state the system is in, i.e., whether or not it has yet been repaired, is unknown to the observer, and he can draw conclusions as to whether or not the system is repaired only by observing the basic data: the successive failure times (or, equivalently, the times between failures).

Finally, it is possible to allow for the system to start off in a repaired state by assigning

$$p_0 = \text{prob. (system is in R at the start of the test)}.$$

Except for one situation to be considered later, however, we shall always assume that $p_0 = 0$.

In the above model, it is easy to see that since the system ultimately* will go to state R, if $\mu < \lambda$, the failure rate of the system will eventually decrease, and thus the reliability will grow. On the other hand, if (for some unforeseen reason) $\mu > \lambda$, it is possible to degrade the system reliability by such a test routine.

2.2 SOME BAYESIAN CONSIDERATIONS

If the numerical values of the parameters a , μ and λ , defined above, are known, then, as will be shown, it becomes a straightforward problem to make probabilistic statements about the failure rate r , at any time, on the basis of any amount of failure information. This is essentially because the value of r depends only upon the state of nature (U or R), and the transition from U to R is the extremely simple process shown in Figure 1. If the values

*As long as $a \neq 0$.

of these parameters are unknown, however, then various methods must be used in order to obtain estimates of them and then, in turn, to make statements about r . This quest is, of course, within the purview of classical statistics, and much has been written concerning the estimation of parameters of models similar to the one treated here and associated confidence intervals (see for example [1]).

The classical approach is, in essence, to 1) define some estimator (of r in this case), examine it for unbiasedness, efficiency, sufficiency, etc.; and then to 2) define an interval, the end points of which are random variables derived from the observed data, which will contain the true value of the parameter with some pre-determined probability.

The approach we choose to take is a purely inferential one. We state that before any experimentation is done the failure rates associated with states U and R are, respectively, the random variables λ and μ . (The sampling process associated with them, if one finds it necessary to imagine such, is the process of selecting a system to test from a batch of systems, the resultant picked system having associated failure rates that are thus random variables selected from the population consisting of all possible systems to be tested.)

We shall also assume that the repair probability a is known. (An obvious extension of the model results if a is also assumed to be a random variable.)

The joint probability density function of the random variables $\underline{\lambda}$ and $\underline{\mu}$, before experimentation begins, must be given, and it is assumed that this is in fact known. This (most likely subjective) prior density function is defined to be

$$f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu | H).$$

After some experimentation and possible correction has gone on and a series of failure times $\vec{t}(n) = (t_1, t_2, \dots, t_n)$ has been noted, then use of the definition of conditional probability allows one to determine the "posteriori" density function.

$$f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu | H, \vec{t}(n)).$$

Since the failure rate of the system at any time is a function of both $\underline{\lambda}$ and $\underline{\mu}$, it is itself a random variable \underline{r} , with its own conditional p.d.f.

The purpose of this study is to in fact determine this density function for \underline{r} , both at the outset of a test period and as a function of a given set of subsequent failure times. In addition, we shall make statements concerning the density function, and its moments, for the failure rate \underline{r} at any given time in the future.

2.3 KNOWN λ AND μ : RELIABILITY PROJECTION

Let us first suppose that λ and μ are deterministic and their exact numerical values are known. The failure rate \underline{r} is still a random variable, however, since it depends upon whether the state of nature is U or R, and that is itself probabilistically determined. The p.d.f. for \underline{r} is easily determined.

With a total test time of τ , the p.d.f. for \underline{r} is $\underline{f}_r(r; \tau)$

$$\underline{f}_r(r; \tau) = \delta(r - \lambda)P(U_\tau) + \delta(r - \mu)P(R_\tau) \quad (1)$$

where

$P(U_\tau)$ = prob. {system is in U after total test time τ }

$P(R_\tau)$ = prob. {system is in R after total test time τ }

The delta function notation is used as a convenient way to write a p.d.f. for the (at this point) discrete random variable \underline{r} .

In what follows we assume that the system starts out in the unrepaired state P, so that $p_0 = 0$. (The development can be easily extended when $p_0 \neq 0$, and this will be done in a later section, where the start of the corrective testing period, $t = 0$, occurs after some previous amount of testing.)

In order to calculate $P(U_\tau) = 1 - P(R_\tau)$, we note that the event (U_τ) can be decomposed into a union of the mutually exclusive events (U_τ, F_i) where

(F_i) = event {the transition from U to R takes place on the i^{th} failure}

so that

$$(U_\tau) = \bigcup_{i=1}^{\infty} (U_\tau, F_i). \quad (2)$$

Since the F_i are mutually exclusive events, we have

$$P(U_\tau) = \sum_{i=1}^{\infty} P(U_\tau, F_i) = \sum_{i=1}^{\infty} P(U_\tau | F_i) P(F_i) \quad (3)$$

The number of the failure at which the transition from U to R takes place is geometrically distributed with parameter a , so that

$$P(F_i) = a(1 - a)^{i-1}. \quad (4)$$

Furthermore, we see that

$$\begin{aligned} P(U_\tau | F_i) &= \text{prob. \{system is in U at } \tau \text{ given it goes to R at } i^{\text{th}} \text{ failure}\}} \\ &= \text{prob. \{less than } i \text{ failures in time } \tau \text{ while in U}\}} \\ &= \sum_{j=0}^{i-1} \frac{(\lambda \tau)^j}{j!} e^{-\lambda \tau} \end{aligned} \quad (5)$$

which all combine to give

$$P(U_\tau) = \sum_{i=1}^{\infty} \sum_{j=0}^{i-1} \frac{(\lambda \tau)^j}{j!} e^{-\lambda \tau} a(1 - a)^{i-1} \quad (6)$$

Changing the order of the summation gives

$$\begin{aligned} P(U_\tau) &= \sum_{j=0}^{\infty} \sum_{i=j+1}^{\infty} \frac{(\lambda \tau)^j}{j!} e^{-\lambda \tau} a(1 - a)^{i-1} \\ &= \sum_{j=0}^{\infty} \frac{(\lambda \tau)^j}{j!} e^{-\lambda \tau} (1 - a)^j = e^{-a\lambda \tau} \end{aligned} \quad (7)$$

This result can be verified by noting that the rate of transition from U to R is $a\lambda$, since

$$\begin{aligned} &\text{prob. \{transition from U to R in } \Delta\tau\}} \\ &= \text{prob. \{failure in } \Delta\tau | U\}} \text{prob. \{repair\}} \\ &= \lambda \Delta\tau a \end{aligned}$$

and, thus, the probability of no transition in time t is, from the Poisson

distribution, $e^{-a\lambda\tau}$. The longer derivation is useful, however, in that it indicates a technique to be used again below.

The above equations thus show that the p.d.f. of the failure rate \underline{r} at time τ after start of testing is

$$f_{\underline{r}}(r;\tau) = \delta(r-\lambda)e^{-a\lambda\tau} + \delta(r-\mu)(1 - e^{-a\lambda\tau}) \quad (8)$$

Note that this expression reflects a probability statement made before the process starts. In other words, we can interpret the quantities

$$\begin{aligned} E(\underline{r};\tau) &\equiv \int_0^{\infty} r f_{\underline{r}}(r;\tau) = \lambda e^{-a\lambda\tau} + \mu(1 - e^{-a\lambda\tau}) \\ &= \mu + (\lambda - \mu)e^{-a\lambda\tau} \end{aligned} \quad (9)$$

and

$$\begin{aligned} V(\underline{r};\tau) &\equiv \int_0^{\infty} [r - E(\underline{r};\tau)]^2 f_{\underline{r}}(r;\tau) \\ &= (\lambda - \mu)^2 e^{-a\lambda\tau}(1 - e^{-a\lambda\tau}) \end{aligned} \quad (10)$$

to be the present projection of what the mean and variance of the failure rate \underline{r} will be at time τ (in the future) after corrective testing.

These projections are useful in themselves as aids to reliability prediction. That is, if we know the values of the unrepaired and repaired failure rates and the value of the repair probability a , then equation (9) gives an estimate* of what the reliability will be at some time τ after testing begins, and equation (10) (actually, the square root of $V(r;\tau)$) gives an indication of the preciseness of that estimate. The behavior of these

*Optimal (i.e., cost-minimizing) for a quadratic loss function.

quantities satisfy intuition: the expectation of the failure rate starts off at λ and approaches μ . The variance starts at zero (we know $r = \lambda$ at $\tau = 0$), and returns to zero as $\tau \rightarrow \infty$ (r will certainly be equal to μ by that time, as long as $a \neq 0$), with an interesting maximum occurring at $\tau = \frac{1}{a\lambda}$.

2.4 KNOWN λ AND μ : RELIABILITY INFERENCE

All of the above analysis has been made under the consideration that the test was yet to be done. The analysis is extended now to the situation where testing has been going on for a time τ , and n failures have been observed at times $t_1, t_2, \dots, t_n = \vec{t}(n)$, where $t_n \leq \tau < t_{n+1}$. (For ease in notation we shall now let $\vec{t} \equiv \vec{t}(n)$, with the understanding that the vector is of dimension n .)

Again, assuming still that μ and λ are deterministic and known, we would like to calculate the appropriate conditional p.d.f. for the failure rate: $f_{\underline{r}}(r | \vec{t}, \tau)$. To do so we shall need to calculate $P(R_{\tau} | \vec{t})$. This is shown by extending equation (1) of the preceding section,

$$f_{\underline{r}}(r | \vec{t}; \tau) = \delta(r - \lambda) P(U_{\tau} | \vec{t}) + \delta(r - \mu) P(R_{\tau} | \vec{t}) \quad (11)$$

We again make use of the events F_i to write

$$\begin{aligned} P(U_{\tau} | \vec{t}) &= \sum_{i=1}^{\infty} P(U_{\tau}, F_i | \vec{t}) \\ &= \sum_{i=1}^{\infty} P(U_{\tau} | F_i, \vec{t}) P(F_i | \vec{t}) \end{aligned} \quad (12)$$

But now we see that

$$P(U_\tau | F_i, \vec{t}) = \text{prob. } \{ \text{the system is in U at } \tau \text{ given it goes to R at} \\ \text{the } i^{\text{th}} \text{ failure, and failures are observed at} \\ t_1, t_2, \dots, t_n \text{ and } t_n \leq \tau < t_{n+1} \}$$

$$= \begin{cases} 0 & \text{if } i \leq n \\ 1 & \text{if } i > n \end{cases} \quad (13)$$

so that equation (12) becomes

$$P(U_\tau | \vec{t}) = \sum_{i=n+1}^{\infty} P(F_i | \vec{t}). \quad (14)$$

Using Bayes' rule

$$P(F_i | \vec{t}) = \frac{P(\vec{t} | F_i) P(F_i)}{P(\vec{t})} = \frac{P(\vec{t} | F_i) a(1-a)^{i-1}}{P(\vec{t})} \quad (15)$$

Under the condition that $i > n$ (i.e., for all terms in the sum in equation (14)), and in fact the i^{th} failure is observed to lie between t_i and $t_i + dt_i$

$$P(\vec{t} | F_i) = \lambda e^{-\lambda t_1} \lambda e^{-\lambda(t_2 - t_1)} \dots \lambda e^{-\lambda(t_n - t_{n-1})} e^{-\lambda(\tau - t_n)} dt_1 dt_2 \dots dt_n \quad (16)$$

$$= \lambda^n e^{-\lambda \tau} d\vec{t} \quad (17)$$

since the times between the first n failures, given that transition to R occurs at some failure after the n^{th} , are identically distributed exponential r.v.'s with common parameter λ . The last term in equation (17), $e^{-\lambda(\tau - t_n)}$, is due to the fact that no failures are observed in the interval (t_n, τ) .

Combining this result with equations (14) and (15) yields

$$\begin{aligned}
P(U_\tau | \vec{t}) &= \sum_{i=n+1}^{\infty} \frac{\lambda^n e^{-\lambda\tau} a(1-a)^{i-1} d\vec{t}}{P(\vec{t})} \\
&= \frac{\lambda^n e^{-\lambda\tau} (1-a)^n d\vec{t}}{P(\vec{t})}
\end{aligned} \tag{18}$$

We now turn our attention to calculating $P(R_\tau | \vec{t})$ in much the same fashion:

$$\begin{aligned}
P(R_\tau | \vec{t}) &= \sum_{i=1}^{\infty} P(R_\tau, F_i | \vec{t}) \\
&= \sum_{i=1}^{\infty} P(R_\tau | F_i, \vec{t}) P(F_i | \vec{t})
\end{aligned} \tag{19}$$

Here we see that

$$P(R_\tau | F_i, \vec{t}) = \begin{cases} 1 & \text{if } i \leq n \\ 0 & \text{if } i > n \end{cases} \tag{20}$$

so that

$$\begin{aligned}
P(R_\tau | \vec{t}) &= \sum_{i=1}^n P(F_i | \vec{t}) \\
&= \sum_{i=1}^n \frac{P(\vec{t} | F_i) P(F_i)}{P(\vec{t})} = \frac{\sum_{i=1}^n P(\vec{t} | F_i) a(1-a)^{i-1}}{P(\vec{t})}
\end{aligned} \tag{21}$$

By the same arguments that lead to equation (17) we find that, when $i \leq n$

$$\begin{aligned}
P(\vec{t} | F_i) &= \lambda e^{-\lambda t_1} \lambda e^{-\lambda(t_2 - t_1)} \dots \lambda e^{-\lambda(t_i - t_{i-1})} \mu e^{-\mu(t_{i+1} - t_i)} \\
&\quad \dots \mu e^{-\mu(t_n - t_{n+1})} \dots e^{-\mu(\tau - t_n)} dt_1 dt_2 \dots dt_n \\
&= \lambda^i e^{-\lambda t_i} \mu^{n-i} e^{-\mu(\tau - t_i)} d\vec{t}
\end{aligned} \tag{22}$$

Using this in equation (9) gives

$$P(R_\tau | \vec{t}) = \frac{\sum_{i=1}^n \lambda^i e^{-\lambda t_i} \mu^{n-i} e^{-\mu(\tau-t_i)} a(1-a)^{i-1} d\vec{t}}{P(\vec{t})} \quad (23)$$

In order to evaluate $P(\vec{t})$, the common denominator in equations (18) and (23), we finally note that since (R_τ) and (U_τ) are exhaustive and mutually exclusive

$$P(R_\tau | \vec{t}) + P(U_\tau | \vec{t}) = 1$$

which, by use of equations (18) and (23) gives

$$\begin{aligned} P(U_\tau | \vec{t}) &= 1 - P(R_\tau | \vec{t}) \\ &= \frac{\lambda^n e^{-\lambda \tau} (1-a)^n}{L(\vec{t}; \lambda, \mu)} \end{aligned} \quad (24)$$

where the function $L(\vec{t}; \lambda, \mu)$ is defined to be

$$\begin{aligned} L(\vec{t}; \lambda, \mu) &\equiv \sum_{i=1}^n \lambda^i e^{-\lambda t_i} \mu^{n-i} e^{-\mu(\tau-t_i)} a(1-a)^{i-1} + \lambda^n e^{-\lambda \tau} (1-a)^n \\ &= P(\vec{t})/d\vec{t} \end{aligned} \quad (25)$$

Combining all this with equation (11) gives, for the density function of the failure rate \underline{r} , having observed failures at t_1, t_2, \dots, t_n during a test period of length τ :

$$\underline{f}_{\underline{r}}(\underline{r} | \vec{t}; \tau) = \frac{\delta(r-\mu) \sum_{i=1}^n \lambda^i e^{-\lambda t_i} \mu^{n-i} e^{-\mu(\tau-t_i)} a(1-a)^{i-1} + \delta(r-\lambda) \lambda^n e^{-\lambda \tau} (1-a)^n}{L(\vec{t}; \lambda, \mu)} \quad (26)$$

Equations (24), (25), and (26) are the only ones necessary to make inferential statements about the reliability at time τ , given failures at times t_1, t_2, \dots, t_n , and given the values of λ, μ and a .

For example, let us suppose that $\mu = 0$ (a repaired system never fails). Since

$$E(\underline{r} | \vec{t}; \tau) = \int_0^{\infty} r f_{\underline{r}}(r | \vec{t}; \tau) dr$$

we find that

$$E(\underline{r} | \vec{t}; \tau) = \frac{\lambda e^{-\lambda \tau} (1-a)}{a e^{-\lambda t_n} + (1-a) e^{-\lambda \tau}} = \frac{\lambda e^{-\lambda(\tau-t_n)}}{\frac{a}{1-a} + \lambda e^{-\lambda(\tau-t_n)}} \quad (27)$$

and

$$P(U_{\tau} | \vec{t}) = 1 - P(R_{\tau} | \vec{t}) = \frac{e^{-\lambda(\tau-t_n)}}{\frac{a}{1-a} + e^{-\lambda(\tau-t_n)}} \quad (28)$$

In this case it becomes apparent that inferential statements can be made with only the information consisting of the length of time since the last failure ($\tau-t_n$). This, of course, is intuitively clear, since, if $\mu = 0$, at the time of the last failure the system couldn't possibly have been repaired.

2.5 UNKNOWN λ AND μ : RELIABILITY PROJECTION

We come now to the more interesting and practical situation: that where the parameters λ and μ of the process are unknown at the start of the testing. Inferential statements about the values of these will come in

the next section. Here we will be concerned with only deriving predictive statements analagous to those implied by equations (9) and (10).

The basic technique used here is to simply consider λ and μ to be random variables $\underline{\lambda}$ and $\underline{\mu}$, with respective p.d.f.'s $f_{\underline{\lambda}}(\lambda|H)$ and $f_{\underline{\mu}}(\mu|H)$, or possibly, a joint p.d.f. $f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu|H)$. These a priori density functions are, at least at the start of experimentation, most probably subjective ones. That is, they represent all information available, at the time, relevant to the failure rates in question and expressed in terms of an appropriate density function*. If some quantitative information is available, from previous tests, etc., then of course these density functions should be conditioned not only upon the event H , but all other observed relevant data.

As a first step, we re-write equation (8) with the notation expanded to emphasize the fact that $\underline{\lambda}$ and $\underline{\mu}$ are, in that equation, deterministic and have known values λ and μ , respectively. In other words,

$$f_{\underline{r}}(r; \tau, \lambda, \mu) \equiv f_{\underline{r}}(r; \tau, \underline{\lambda} = \lambda, \underline{\mu} = \mu)$$

so that

$$f_{\underline{r}}(r; \tau, \lambda, \mu) = \delta(r - \lambda) e^{-a\lambda\tau} + \delta(r - \mu) (1 - e^{-a\lambda\tau}) \quad (29)$$

We now use the well-known fact that for any probability that is itself conditioned so that it is a function of a realization of a r.v., i.e.,

*The best techniques for producing such subjective functions are, and will probably always be, subject to a great deal of controversy. We side-step these philosophical issues here. The interested reader is referred to the copious literature on the subject, for example [7].

$P(A|\underline{x} = x)$, the unconditioned probability is simply the expectation of the conditioned one, i.e.,

$$P(A) = \int_{-\infty}^{\infty} P(A|\underline{x} = x) f_{\underline{x}}(x) dx \quad (30)$$

Using this relation, we may write in place of equation (8)

$$f_{\underline{r}}(r; \tau) = \int_0^{\infty} \int_0^{\infty} f_{\underline{r}}(r; \tau, \lambda, \mu) f_{\underline{\lambda\mu}}(\lambda, \mu | H) d\lambda d\mu.$$

In all that follows we shall assume that $\underline{\lambda}$ and $\underline{\mu}$ are independent, for ease of notation, so that we may write

$$f_{\underline{\lambda\mu}}(\lambda, \mu) = f_{\underline{\lambda}}(\lambda) f_{\underline{\mu}}(\mu).$$

The discussion, however, can be easily extended to the case when they are dependent variables. We shall, for convenience, also drop the conditioning event H , since all statements that can be made are all eventually conditioned upon prior experience.

Performing the indicated integration, we find

$$\begin{aligned} f_{\underline{r}}(r; \tau) &= \int_0^{\infty} \int_0^{\infty} [\delta(r - \lambda) e^{-a\lambda\tau} + \delta(r - \mu) (1 - e^{-a\lambda\tau})] f_{\underline{\lambda}}(\lambda) f_{\underline{\mu}}(\mu) d\lambda d\mu \\ &= f_{\underline{\lambda}}(r) e^{-ar\tau} + f_{\underline{\mu}}(r) \int_0^{\infty} (1 - e^{-a\xi\tau}) f_{\underline{\lambda}}(\xi) d\xi \end{aligned} \quad (31)$$

from which we may derive

$$E(r; \tau) = \int_0^{\infty} \xi f_{\underline{\lambda}}(\xi) e^{-a\xi\tau} d\xi + E(\underline{\mu}) \int_0^{\infty} (1 - e^{-a\xi\tau}) f_{\underline{\lambda}}(\xi) d\xi \quad (32)$$

*For example, see Parzen [11] p. 336.

An expression for $V(r;\tau)$ may also be derived, but the specific form is complicated and does not provide any easy interpretation.

As an example of the use of equation (32), consider the case where, again, μ is known and is in fact equal zero (or, equivalently, it is a r.v. with p.d.f. $f_{\underline{\mu}}(\mu) = \delta(\mu)$). Then $E(r;\tau)$ becomes, from (32)

$$E(\underline{r};\tau) = \int_0^{\infty} \xi f_{\underline{\lambda}}(\xi) e^{-a\xi\tau} d\xi \quad (33)$$

The behavior of this expected value of failure rate at a time τ into the future (under the corrective test program) can be explored by selecting an appropriate form for the prior p.d.f. on $\underline{\lambda}$. For convenience, we select for this prior density function the conjugate form [12] gamma distribution

$$f_{\underline{\lambda}}(\lambda) = \begin{cases} \frac{\beta^\alpha}{\Gamma(\alpha)} \lambda^{\alpha-1} e^{-\beta\lambda} & 0 \leq \lambda \leq \infty \\ 0 & \text{otherwise} \end{cases} \quad (34)$$

which has the moments

$$E(\underline{\lambda}) = \frac{\alpha}{\beta}$$

$$V(\underline{\lambda}) = \frac{\alpha}{\beta^2}$$

This distribution thus has enough freedom for the fitting of a desired mean and variance by appropriate selection of the constants α and β .

Putting equation (34) into (32) yields

$$\begin{aligned}
 E(\underline{r}; \tau) &= \frac{\beta^\alpha}{\Gamma(\alpha)} \frac{\Gamma(\alpha+1)}{(\beta + a\tau)^{\alpha+1}} = \frac{\alpha}{\beta} \left(\frac{\beta}{\beta + a\tau} \right)^{\alpha+1} \\
 &= E(\underline{\lambda}) \left(1 + \frac{a\tau}{\beta} \right)^{-(\alpha+1)}
 \end{aligned}$$

2.6 UNKNOWN λ AND μ : RELIABILITY INFERENCE

The problem of inferring the value of \underline{r} after the observation of a data vector $t = t(n)$ is, of course, complicated by the fact that now $\underline{\lambda}$ and $\underline{\mu}$ are also random variables: A complete solution must also make inferential statements about the posterior distributions for these rates as well as for \underline{r} .

These statements, via the appropriate posterior density functions, may be easily made, however, by the judicious use of equation (30). For example, we note that equation (24) now should be written

$$P(U_\tau | \vec{t}; \underline{\lambda} = \lambda, \underline{\mu} = \mu) = \frac{\lambda^n e^{-\lambda\tau} (1-a)^n}{L(\vec{t}; \lambda, \mu)} \quad (35)$$

The unconditional probability that the system is still in the unrepaired state becomes, using Bayes' Rule twice, and all limits of integration from 0 to ∞ .

$$\begin{aligned}
 P(U_\tau | \vec{t}) &= \int \int P(U_\tau | \vec{t}; \underline{\lambda} = \lambda, \underline{\mu} = \mu) f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu | \vec{t}) d\lambda d\mu \\
 &= \int \int P(U_\tau | \vec{t}; \underline{\lambda} = \lambda, \underline{\mu} = \mu) \frac{L(\vec{t}; \lambda, \mu) f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu) d\lambda d\mu}{\int \int L(\vec{t}; \lambda, \mu) f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu) d\lambda d\mu} \\
 &= \frac{\int \int P(U_\tau, \vec{t} | \underline{\lambda} = \lambda, \underline{\mu} = \mu) f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu) d\lambda d\mu}{\int \int L(\vec{t}; \lambda, \mu) f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu) d\lambda d\mu}
 \end{aligned}$$

$$= \frac{\int \int \lambda^n e^{-\lambda \tau} (1-a)^n f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu) d\lambda d\mu}{\int \int L(\vec{t}; \lambda, \mu) f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu) d\lambda d\mu} \quad (36)$$

In addition, $P(R_\tau | \vec{t})$ may be obtained by noting that

$$= 1 - P(R_\tau | \vec{t}) \quad (37)$$

Similarly, it may be shown that the appropriate posterior density functions for the rates $\underline{\lambda}$ and $\underline{\mu}$ are

$$\begin{aligned} f_{\underline{\lambda}}(\lambda | \vec{t}; \tau) &= \frac{P(\vec{t} | \underline{\lambda} = \lambda) f_{\underline{\lambda}}(\lambda)}{\int P(\vec{t} | \underline{\lambda} = \lambda) f_{\underline{\lambda}}(\lambda) d\lambda} \\ &= \frac{\int L(\vec{t}; \mu, \lambda) f_{\underline{\lambda}}(\lambda) f_{\underline{\mu}}(\mu) d\mu}{\int \int L(\vec{t}; \mu, \lambda) f_{\underline{\lambda}}(\lambda) f_{\underline{\mu}}(\mu) d\lambda d\mu} \end{aligned} \quad (38)$$

and

$$f_{\underline{\mu}}(\mu | \vec{t}; \tau) = \frac{\int L(\vec{t}; \mu, \lambda) f_{\underline{\lambda}}(\lambda) f_{\underline{\mu}}(\mu) d\lambda}{\int \int L(\vec{t}; \mu, \lambda) f_{\underline{\lambda}}(\lambda) f_{\underline{\mu}}(\mu) d\lambda d\mu} \quad (39)$$

where we have let $f_{\underline{\lambda}\underline{\mu}}(\lambda, \mu) = f_{\underline{\lambda}}(\lambda) f_{\underline{\mu}}(\mu)$ for ease of notation.

Finally, the same sort of manipulation leads to

$$f_{\underline{r}}(r | \vec{t}; \tau) = \frac{\int \sum_{i=1}^n \lambda^i e^{-\lambda t_i} r^{n-1} e^{-r(\tau-t_1)} a(1-a)^{i-1} f_{\underline{\lambda}}(\lambda) d\lambda + r^n e^{-r\tau} (1-a)^n}{\int \int L(\vec{t}; \lambda, \mu) f_{\underline{\lambda}}(\lambda) f_{\underline{\mu}}(\mu) d\lambda d\mu} \quad (40)$$

Although these equations seem formidable, they are extremely useful and valuable and provide all the information necessary for inferential statements about the system reliability, given an observed set of failure times.

In particular, knowledge of the expected values of the random variables λ , μ and r , given \vec{t} , gives the experimenter good estimates of the value of

- a) the failure rate before testing began: equation (38)
- b) the eventual value of the failure rate after unlimited correctional testing: equation (39)
- c) the present value of the failure rate: equation (40)

Additionally, the probability $P(R_r | \vec{t})$ that the system has in fact been repaired is given directly by equation (37).

As is common in all Bayesian inference schemes, the foregoing development is liable, with some justification, to the criticism that the results are dependent upon the particular prior distributions used: $f_{\lambda}(\lambda)$ and $f_{\mu}(\mu)$. This is indeed so, but the real concern should be with the sensitivity of the results to variations and/or extremes in the selection of prior functions. In particular, it is certainly possible to select the prior distributions with sufficiently large variances, so that the result of the analysis becomes relatively independent of the prior expectations.

On the other hand, if the failure rates in question are to any degree known in advance, it seems unreasonable not to allow the analyst to make use of his knowledge -- particularly for the making of projections.

3. THE DISCRETE MODEL

3.1 MODEL DESCRIPTION

A model similar to the one discussed above is now developed for the case where a system exhibits "discrete" failure behavior. That is, the system undergoes "trials", and at each trial the system either succeeds or fails. We assume that these trials are independent (the equivalent of the assumption of exponential behavior for the continuous model). A convenient and appropriate measure of reliability of the system at any time is simply $p = 1 - q$, where

p = probability {success on the next trial}

q = probability {failure on the next trial}

In order to model a reliability growth effect, we again consider the system to start in state U, from which it has probability a of making a transition to state R after every failure. We then define the probabilities

u = probability {system fails on a trial given in state U}

v = probability {system fails on a trial given in state R}

The analysis now proceeds exactly as in the preceding sections, and requires only some obvious notational changes (to account for the discrete character of the failure data) and additions.

Let:

$\vec{x} \equiv \{x_1, x_2, \dots, x_n\}$ = the observed data vector after n trials,
where $x_i = 0$ or 1 as the i^{th} trial results in a failure or success, respectively

$y_i = \sum_{k=1}^i x_k \quad (i = 1, 2, \dots, n) = \text{the cumulative number of successes up to and including the } i^{\text{th}} \text{ trial}$

$z_i = n - y_i = \text{the cumulative number of failures up to and including the } i^{\text{th}} \text{ trial}$

3.2 KNOWN u AND v : RELIABILITY PROJECTION

We first consider the case where the failure probabilities u and v are deterministic and known. At the end of N trials, the system failure probability is the random variable q , with p.d.f. $f_q(q; N)$ given by

$$f_q(q; N) = \delta(q-u) P(U_N) + \delta(q-v) P(R_N) \quad (42)$$

in direct analogy with equation (1), where

$P(U_N) = \text{probability \{system is in U after N trials\}}$

$P(R_N) = \text{probability \{system is in R after N trials\}}$

The value of $P(U_N)$ is readily calculated:

$$\begin{aligned} P(U_N) &= [\text{probability \{system not repaired after one trial\}}]^N \\ &= [1 - \text{probability \{system is repaired after one trial\}}]^N \\ &= [1 - au]^N \end{aligned}$$

since all the N trials are in the U state, are independent, and a failure (with probability u) is necessary before a repair (probability a) is made.

Equation (42) then becomes

$$f_q(q; N) = \delta(q-u)(1-au)^N + \delta(q-v)[1 - (1-au)^N] \quad (43)$$

The expectation of the system failure probability at the end of N trials is

$E(\underline{q}; N)$, where

$$\begin{aligned} E(\underline{q}; N) &= \int_0^1 q f_{\underline{q}}(q; N) dq \\ &= u(1-au)^N + v[1 - (1-au)^N] \\ &= v + (u-v)(1-au)^N \end{aligned} \quad (44)$$

3.3 KNOWN u AND v : RELIABILITY INFERENCE

In order to make inferential statements about the random variable \underline{q} (and hence \underline{p}) given some data has been observed, we proceed again in a fashion similar to that used in the analysis of the continuous model. In particular, we may write for the conditional p.d.f. of \underline{q} , given the observed failure data vector \vec{x} :

$$f_{\underline{q}}(q | \vec{x}) = \delta(q-u) P(U_n | \vec{x}) + \delta(q-v) P(R_n | \vec{x}) \quad (45)$$

By defining the event G_i

(G_i) = event {the transition from state U to state R takes place immediately after the i^{th} failure}

we may first of all write

$$\begin{aligned} P(U_n | \vec{x}) &= \sum_{i=1}^{\infty} P(U_n, G_i | \vec{x}) \\ &= \sum_{i=1}^{\infty} P(U_n | G_i, \vec{x}) P(G_i | \vec{x}) \end{aligned} \quad (46)$$

since

$$\bigcup_{i=1}^{\infty} (U_n, G_i | \vec{x}) = (U_n | \vec{x}) .$$

The definition of G_i allows us to write

$$P(U_n | G_i, \vec{x}) = \begin{cases} 0 & i \leq z_n \\ 1 & i > z_n \end{cases}$$

since z_n is the total number of failures observed in the first n trials.

Thus, if $i \leq z_n$, the transition from U to R has taken place at or before the n^{th} trial, and the system cannot be in state U at the n^{th} trial.

Equation (46) can now be written

$$P(U_n | \vec{x}) = \sum_{i=z_n+1}^{\infty} P(G_i | \vec{x}) \quad (47)$$

and, using Bayes' Rule,

$$P(U_n | \vec{x}) = \frac{\sum_{i=z_n+1}^{\infty} P(\vec{x} | G_i) P(G_i)}{P(\vec{x})}$$

The value of $P(G_i)$ is determined from the underlying geometric process with parameter a , so that

$$P(U_n | \vec{x}) = \frac{\sum_{i=z_n+1}^{\infty} P(\vec{x} | G_i) a(1-a)^{i-1}}{P(\vec{x})} \quad (48)$$

We now note that when the transition from U to R takes place at some trial after the n^{th} [i.e., for all terms in the summation in equation (48)], we may write

$$\begin{aligned} P(\vec{x} | G_1) &= u^{1-x_1} (1-u)^{x_1} u^{1-x_2} (1-u)^{x_2} \dots u^{1-x_n} (1-u)^{x_n} \\ &= u^{z_n} (1-u)^{y_n} \end{aligned}$$

since all n trials take place while the system is in the U state. Combining this result with equation (48) gives

$$\begin{aligned} P(U_n | \vec{x}) &= \frac{\sum_{i=z_{n+1}}^{\infty} u^{z_n} (1-u)^{y_n} a(1-a)^{i-1}}{P(\vec{x})} \\ &= \frac{u^{z_n} (1-u)^{y_n} (1-a)^{z_n}}{P(\vec{x})} \end{aligned} \quad (49)$$

The calculation of $P(R_n | \vec{x})$ is also accomplished by use of the exhaustive and exclusive character of the event (G_i) $i = 1, 2, \dots \infty$.

$$\begin{aligned} P(R_n | \vec{x}) &= \sum_{i=1}^{\infty} P(R_n, G_i | \vec{x}) \\ &= \sum_{i=1}^{\infty} P(R_n | G_i, \vec{x}) P(G_i | \vec{x}) \end{aligned} \quad (50)$$

The value of $P(R_n | G_i, \vec{x})$ is determined by the same arguments that led to equation (47):

$$P(R_n | G_i, \vec{x}) = \begin{cases} 1 & i \leq z_n \\ 0 & i > z_n \end{cases} \quad (51)$$

so that equation (50) becomes

$$P(R_n | \vec{x}) = \sum_{i=1}^{z_n} P(G_i | \vec{x})$$

and, using Bayes' Rule and $P(G_i) = a(1-a)^{i-1}$,

$$P(R_n | \vec{x}) = \frac{\sum_{i=1}^{z_n} P(\vec{x} | G_i) a(1-a)^{i-1}}{P(\vec{x})} \quad (52)$$

where the summation is defined to be zero when $z_n = 0$.

Finally, we note that when $i \leq z_n$

$$\begin{aligned} P(\vec{x} | G_i) &= \left[u^{1-x_1} (1-u)^{x_1} u^{1-x_2} (1-u)^{x_2} \dots u^{1-x_i} (1-u)^{x_i} \right] \times \\ &\quad \left[v^{1-x_{i+1}} (1-v)^{x_{i+1}} \dots v^{1-x_n} (1-v)^{x_n} \right] \\ &= u^{1-y_i} (1-u)^{y_i} v^{n-i-y_n+y_i} (1-v)^{y_n-y_i} \\ &= u^{z_i} (1-u)^{y_i} v^{z_n-z_i} (1-v)^{y_n-y_i} \end{aligned} \quad (53)$$

so that

$$P(R_n | \vec{x}) = \frac{\sum_{i=1}^{z_n} u^{z_i} (1-u)^{y_i} v^{z_n-z_i} (1-v)^{y_n-y_i} a(1-a)^{i-1}}{P(\vec{x})} \quad (54)$$

Complete inferential statements about the failure probability q , given the observed data \vec{x} , may now be readily made using the posterior p.d.f.

$f_q(q | \vec{x})$. This has been obtained, essentially, since we now need to

simply substitute the expressions for $P(U_n | \vec{x})$ and $P(R_n | \vec{x})$ (from equations (49) and (54), respectively) into equation (45). Note that the common term of $P(\vec{x})$ in the denominators of equations (49) and (54) can be evaluated by means of

$$P(U_N | \vec{x}) + P(R_n | \vec{x}) = 1$$

3.4 UNKNOWN u AND v : RELIABILITY PROJECTION

When the failure probabilities u and v are unknown, we proceed as in section 2.5 by treating these parameters as random variables \underline{u} and \underline{v} , with joint p.d.f. $f_{\underline{uv}}(u, v) = f_{\underline{uv}}(u, v | H)$. Again, we shall (for ease in development) assume that \underline{u} and \underline{v} are independent, so that

$$f_{\underline{uv}}(u, v) = f_{\underline{u}}(u) f_{\underline{v}}(v)$$

Use of the technique illustrated by equation (30) gives the following results. (Intermediate steps have been left out. The development parallels that of section 2.5)

$$\begin{aligned} f_{\underline{q}}(q; N) &= \int_0^1 \int_0^1 \{ \delta(q-u)(1-au)^N + \delta(q-v)[1-(1-au)^N] \} f_{\underline{uv}}(u, v) du dv \\ &= (1-aq)^N f_{\underline{u}}(q) + f_{\underline{v}}(q) \int_0^1 [1-(1-a\xi)^N] f_{\underline{u}}(\xi) d\xi \end{aligned} \quad (55)$$

The projected expectation of the failure probability at the end of N trials is

$$\begin{aligned} E(q; N) &= \int_0^1 q f_{\underline{q}}(q; N) dq \\ &= \int_0^1 \xi f_{\underline{u}}(\xi) (1-a\xi)^N d\xi + E(\underline{v}) \int_0^1 [1-(1-a\xi)^N] f_{\underline{v}}(\xi) d\xi \end{aligned} \quad (56)$$

3.5 UNKNOWN u AND v : RELIABILITY INFERENCE

When a data vector \vec{x} has been observed, and u and v are random variables with prior p.d.f. $f_{uv}(u, v)$, conditional density functions on u , v and q can be derived in a manner parallel to that used for the continuous case in section 2.6.

To keep the expressions concise, we define the following terms:

$$P(U_N, \vec{x}; u) = u^{z_n} (1-u)^{y_n} (1-a)^{z_n} \quad (57)$$

$$P(R_n, \vec{x}; u, v) = \sum_{i=1}^{z_n} u^{z_i} (1-u)^{y_i} v^{z_n - z_i} (1-v)^{y_n - y_i} a(1-a)^{i-1} \quad (58)$$

$$P(\vec{x}; u, v) = P(U_N, \vec{x}; u) + P(R_n, \vec{x}; u, v) \quad (59)$$

$$P(\vec{x}) = \int_0^1 \int_0^1 P(\vec{x}; u, v) f_{uv}(u, v) du dv \quad (60)$$

The posterior density functions of interest then become (after intermediate steps similar to those in section 2.6)

$$f_u(u | \vec{x}) = \frac{\int_0^1 P(\vec{x}; u, v) f_{uv}(u, v) dv}{P(\vec{x})} \quad (61)$$

$$f_v(v | \vec{x}) = \frac{\int_0^1 P(\vec{x}; u, v) f_{uv}(u, v) du}{P(\vec{x})} \quad (62)$$

$$f_q(q | \vec{x}) = \frac{\int_0^1 P(R_n, \vec{x}; u, q) f_u(u) du + P(U_N, \vec{x}; q)}{P(\vec{x})} \quad (63)$$

and the posterior probability that the system has been repaired is

$$P(R_n | \vec{x}) = \frac{\int_0^1 \int_0^1 P(R_n, \vec{x}; u, v) f_{uv}(u, v) du dv}{P(\vec{x})} \quad (64)$$

4. NUMERICAL EXAMPLES

4.1 CONTINUOUS MODEL

A numerical example is now presented to illustrate the use of the results of the previous sections.

The first task is the assignment of appropriate prior probability density functions for the failure rates λ (before repair) and μ (after repair). In order to facilitate calculations it is convenient to assume that these random variables are independent and have prior density functions of the Gamma family, so that

$$f_{\lambda}(\lambda) = \frac{\beta_1^{\alpha_1}}{\Gamma(\alpha_1)} \lambda^{\alpha_1-1} e^{-\beta_1 \lambda} \quad (65)$$

$$f_{\mu}(\mu) = \frac{\beta_2^{\alpha_2}}{\Gamma(\alpha_2)} \mu^{\alpha_2-1} e^{-\beta_2 \mu} \quad (66)$$

Furthermore, we suppose that estimates are available for the moments of \underline{u} and \underline{v} . A particular set of such estimates is

$$\begin{aligned} E(\underline{\lambda}) &= 1 & E(\underline{\mu}) &= .5 \\ \sigma(\underline{\lambda}) &= 1 & \sigma(\underline{\mu}) &= .5 \end{aligned} \quad (67)$$

where $E(\underline{\lambda}) = \int_0^1 \lambda f_{\underline{\lambda}}(\lambda) d\lambda = \text{expected value of } \underline{\lambda}$

$$V(\lambda) = \sigma^2(\underline{\lambda}) = \int_0^1 [\lambda - E(\underline{\lambda})]^2 f_{\underline{\lambda}}(\lambda) d\lambda = \text{variance of } \underline{\lambda}$$

This set of estimates, in conjunction with equations (65) and (66) give

$$\begin{array}{ll} \alpha_1 = 1 & \alpha_2 = 1 \\ \beta_1 = 1 & \beta_2 = 2 \end{array}$$

The repair probability is assumed known and to have value $a = .25$

These figures are selected not with a physical example in mind, but with the intention of displaying the underlying features of the model. Thus we at this point have assumed the following.

. At the start of testing, the system has a constant failure rate λ that is unknown, but is estimated to be about 1 (per unit time). The precision of this estimate is indicated by a standard deviation of 1 (per unit time).

. After every failure an attempt at repair is made. This attempt has probability $a = .25$ of succeeding, i.e., putting the system in the "repaired" state.

. When the system has been repaired, the failure rate decreases to a constant value μ which is unknown, but which (from experience or judicial guessing) can be estimated to be .5 (per unit time) with a standard deviation also of .5 (per unit time).

We now proceed to make statements about: the failure rate after some length of future test time (projection); updated estimates of λ and μ on

the basis of failure data gathered during the experiment (inference); the system failure rate r after observation of failure data.

Projection:

Using the values given above, the p.d.f. for the failure rate r at some time τ after the start of the growth program is, from equation (31)

$$f_{\underline{r}}(r;\tau) = e^{-r(1+.25\tau)} + \frac{.5\tau e^{-2r}}{1+.25\tau} \quad (68)$$

and so the expected value of the failure rate after time τ is, from (32)

$$E(\underline{r}) = \left(\frac{1}{1+.25\tau} \right)^2 + \frac{.5\tau}{(1+.25\tau)} \quad (69)$$

From this expression we see that the expected failure rate will drop halfway between its unrepaired and repaired values after a length of approximately $\tau \approx 12$ units.

Inference:

In order to make inferential statements about $\underline{\lambda}$, $\underline{\mu}$ and \underline{r} , a data vector is needed.

Suppose that failures are observed, after the start of testing, at times 1, 2, 3, 4, 6.2, 8.2, 10.2, so that n = number of failures = 7 and

$$\vec{t} = (1, 2, 3, 4, 6.2, 8.2, 10.2)$$

[This data vector was chosen to intentionally -- and crudely -- simulate a "repair" at $t = 4$ and a decrease in failure rate from 1 to .5]

For any time τ , equations (38), (39) and (40) give the p.d.f. for $\underline{\lambda}$, $\underline{\mu}$ and \underline{r} , respectively; equation (36) gives the probability that the system

has been repaired at or before that time. In our numerical example, we can examine these posterior density functions by finding their means and standard deviations. For the prior parameters and data vector given above, these have been calculated and are shown in Table 1 for values of τ from 0 to 10.2 by increments of $\Delta\tau = .2$ time units.

Projection after Inference:

At this point it is possible to extend the development to describe the following situation.

Suppose that prior parameters have been selected, as above, and the inferential calculations carried out. At time $\tau = 10.2$, after having seen the 7 failures described by \vec{t} , what can we say about the expectation of the failure rate at some time τ' after time $\tau = 10.2$?

In order to answer this question we note that at time $\tau = 10.2$ we have (see Table 1)

$$\begin{aligned} E(\underline{\lambda}) &= .917 & E(\underline{\mu}) &= .543 \\ \sigma(\underline{\lambda}) &= .522 & \sigma(\underline{\mu}) &= .322 & (70) \\ P(R_{12} | \vec{t}) &= .846 \end{aligned}$$

We are now faced with the situation described in the discussion following equation (1). For we may consider the situation to be such that the values of equation (70) describe our total knowledge about $\underline{\lambda}$ and $\underline{\mu}$ up to that point; i.e., they can serve to define a new "prior" density function, with parameters α'_1 , β'_1 , α'_2 and β'_2 .

FAILURES	TIME	E(λ)	$\sigma(\lambda)$	E(μ)	$\sigma(\mu)$	P(R _T)	E(r)	$\sigma(r)$
0	20	314	314	000	000	526	71	96
0	40	314	314	000	000	526	71	96
0	60	314	314	000	000	526	71	96
1	80	314	314	000	000	526	71	96
1	100	314	314	000	000	526	71	96
1	120	314	314	000	000	526	71	96
1	140	314	314	000	000	526	71	96
1	160	314	314	000	000	526	71	96
1	180	314	314	000	000	526	71	96
1	200	314	314	000	000	526	71	96
1	220	314	314	000	000	526	71	96
1	240	314	314	000	000	526	71	96
1	260	314	314	000	000	526	71	96
1	280	314	314	000	000	526	71	96
1	300	314	314	000	000	526	71	96
1	320	314	314	000	000	526	71	96
1	340	314	314	000	000	526	71	96
1	360	314	314	000	000	526	71	96
1	380	314	314	000	000	526	71	96
1	400	314	314	000	000	526	71	96
1	420	314	314	000	000	526	71	96
1	440	314	314	000	000	526	71	96
1	460	314	314	000	000	526	71	96
1	480	314	314	000	000	526	71	96
1	500	314	314	000	000	526	71	96
1	520	314	314	000	000	526	71	96
1	540	314	314	000	000	526	71	96
1	560	314	314	000	000	526	71	96
1	580	314	314	000	000	526	71	96
1	600	314	314	000	000	526	71	96
1	620	314	314	000	000	526	71	96
1	640	314	314	000	000	526	71	96
1	660	314	314	000	000	526	71	96
1	680	314	314	000	000	526	71	96
1	700	314	314	000	000	526	71	96
1	720	314	314	000	000	526	71	96
1	740	314	314	000	000	526	71	96
1	760	314	314	000	000	526	71	96
1	780	314	314	000	000	526	71	96
1	800	314	314	000	000	526	71	96
1	820	314	314	000	000	526	71	96
1	840	314	314	000	000	526	71	96
1	860	314	314	000	000	526	71	96
1	880	314	314	000	000	526	71	96
1	900	314	314	000	000	526	71	96
1	920	314	314	000	000	526	71	96
1	940	314	314	000	000	526	71	96
1	960	314	314	000	000	526	71	96
1	980	314	314	000	000	526	71	96
1	1000	314	314	000	000	526	71	96

Doing so, we find that

$$\begin{aligned}\alpha_1' &= 1.75 & \alpha_2' &= 1.68 \\ \beta_1' &= 1.92 & \beta_2' &= 3.10\end{aligned}$$

In addition, we now have the situation where the value of

$$\begin{aligned}p_0 &= \text{prob \{system is in R at time 0\}} \\ &= P\{R_{12} | \vec{t}\} = .846\end{aligned}$$

A simple argument leads to the modification of equation (8) for the case when $p_0 \neq 0$:

$$f_{\underline{r}}(r; \tau) = \delta(r-\lambda)(1-p_0)e^{-a\lambda\tau} + \delta(r-\mu)[1-(1-p_0)e^{-a\lambda\tau}] \quad (71)$$

and, consequently, equation (31) becomes

$$f_{\underline{r}}(r; \tau) = (1-p_0)f_{\underline{\lambda}}(r)e^{-a\lambda\tau} + f_{\underline{\mu}}(r) \int_0^\infty [1-(1-p_0)e^{-a\xi\tau}] f_{\underline{\lambda}}(\xi) d\xi \quad (72)$$

Taking the expectation of equation (72), using the primed prior parameters, we get

$$E(\underline{r} | \vec{t}; \tau') = \text{expected value of failure rate time } \tau' \text{ after } \tau = 12, \\ \text{given } \vec{t}$$

$$\begin{aligned}&= (1-p_0) \frac{\alpha_1'}{\beta_1'} \left(\frac{\beta_1'}{\beta_1' + a\tau'} \right)^{\alpha_1'+1} + \frac{\alpha_2'}{\beta_2'} \left[1 - (1-p_0) \left(\frac{\beta_1'}{\beta_1' + a\tau'} \right)^{\alpha_1'} \right] \\ &= .543 + \frac{.485(.72 - .136\tau')}{(1.92 + .25\tau')^{2.75}}\end{aligned}$$

Sensitivity:

The model has not been fully evaluated with regard to the sensitivity of results to values of the prior parameters, errors in estimation of a , etc.

However, examples for various cases have been calculated.

Tables 3 through 6 show $E(\lambda)$, $\sigma(\lambda)$, $E(\mu)$, $\sigma(\mu)$, $P(R_\tau)$, $E(r)$ and $\sigma(r)$ all conditioned upon the data vector $\vec{t} = (1, 2, 3, 4, 6.2, 8.2, 10.2)$ and evaluated at $\tau = 0$ to 10.2 by increments of $\Delta\tau = .2$ time units. These calculations contain the prior parameters as shown in Table 2.

Table	α_1	β_1	α_2	β_2	$E(\lambda)$	$\sigma(\lambda)$	$E(\mu)$	$\sigma(\mu)$	a
1	1	1	1	2	1	1	.5	.5	.25
3	4	4	4	8	1	.5	.5	.25	.25
4	1	2	1	4	.5	.5	.25	.25	.25
5	4	4	4	8	1	.5	.5	.25	.12
6	4	4	4	8	1	.5	.5	.25	.50

TABLE 2

Prior Parameters Used in Calculations of Tables 3-6

4.2 DISCRETE MODEL

For the discrete model, numerical calculations become simplified when the prior probability density functions for the failure probabilities $\underline{\mu}$ and $\underline{\nu}$ are of the Beta family of p.d.f.'s, where

$$B(x; \alpha, \beta) = \frac{\Gamma(\beta)}{\Gamma(\alpha)\Gamma(\beta-\alpha)} x^{\alpha-1} (1-x)^{\beta-\alpha-1} \quad (73)$$

FAILURES	TIME	E(λ)	$\sigma(\lambda)$	E(μ)	$\sigma(\mu)$	P(R _T)	E(r)	$\sigma(r)$
00000	200000	451757	33757	00000	250000	26000	5638	4413
11111	240000	41757	3357	25000	25000	29000	5538	4429
11111	280000	3577	4541	2440	2447	30000	5467	4407
11111	320000	4541	4100	2374	2351	35000	5415	4407
11111	360000	4100	4235	2270	2243	42000	5403	4399
11111	400000	4235	4116	2165	2143	44000	5383	4399
11111	440000	4116	4000	2060	2048	45000	5362	4399
11111	480000	4000	3956	1955	1943	4512	5342	4399
11111	520000	3956	3926	1850	1838	4511	5322	4399
11111	560000	3926	3866	1745	1733	4511	5302	4399
11111	600000	3866	3844	1640	1628	4511	5282	4399
11111	640000	3844	3844	1535	1523	4511	5262	4399
11111	680000	3844	3844	1430	1418	4511	5242	4399
11111	720000	3844	3844	1325	1313	4511	5222	4399
11111	760000	3844	3844	1220	1208	4511	5202	4399
11111	800000	3844	3844	1115	1103	4511	5182	4399
11111	840000	3844	3844	1010	998	4511	5162	4399
11111	880000	3844	3844	905	893	4511	5142	4399
11111	920000	3844	3844	800	788	4511	5122	4399
11111	960000	3844	3844	695	683	4511	5102	4399
11111	1000000	3844	3844	590	578	4511	5082	4399
11111	1040000	3844	3844	485	473	4511	5062	4399
11111	1080000	3844	3844	380	368	4511	5042	4399
11111	1120000	3844	3844	275	263	4511	5022	4399
11111	1160000	3844	3844	170	158	4511	5002	4399
11111	1200000	3844	3844	65	53	4511	4982	4399

TABLE 4

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FAILURES	TIME	$E(\lambda)$	$\sigma(\lambda)$	$E(\omega)$	$\sigma(\omega)$	$P(R_r)$	$E(r)$	$\sigma(r)$
0	20	955	476	500	250	121	940	528
0	40	900	431	500	250	134	874	428
0	60	870	417	500	250	143	846	404
1	80	833	405	495	248	154	820	382
1	100	800	392	493	247	164	807	364
1	120	766	380	490	245	175	793	342
1	140	735	368	487	243	185	784	325
1	160	700	355	483	241	195	770	308
2	180	665	343	479	239	205	756	291
2	200	632	331	475	237	215	744	275
2	220	600	319	471	235	225	731	259
2	240	567	307	467	233	235	719	244
2	260	535	295	463	231	245	707	228
2	280	503	283	459	229	255	696	213
2	300	471	271	455	227	265	684	198
2	320	440	259	451	225	275	673	183
2	340	408	247	447	223	285	662	168
2	360	377	235	443	221	295	651	153
2	380	345	223	439	219	305	640	138
2	400	314	211	435	217	315	629	123
2	420	283	199	431	215	325	618	108
2	440	252	187	427	213	335	607	93
2	460	221	175	423	211	345	596	78
2	480	190	163	419	209	355	585	63
2	500	159	151	415	207	365	574	48
2	520	128	139	411	205	375	563	33
2	540	97	127	407	203	385	552	18
2	560	66	115	403	201	395	541	3
2	580	35	103	399	199	405	530	
2	600	4	91	395	197	415	519	
2	620		79	391	195	425	508	
2	640		67	387	193	435	497	
2	660		55	383	191	445	486	
2	680		43	379	189	455	475	
2	700		31	375	187	465	464	
2	720		19	371	185	475	453	
2	740		7	367	183	485	442	
2	760			363	181	495	431	
2	780			359	179	505	420	
2	800			355	177	515	409	
2	820			351	175	525	398	
2	840			347	173	535	387	
2	860			343	171	545	376	
2	880			339	169	555	365	
2	900			335	167	565	354	
2	920			331	165	575	343	
2	940			327	163	585	332	
2	960			323	161	595	321	
2	980			319	159	605	310	
2	1000			315	157	615	299	
2	1020			311	155	625	288	
2	1040			307	153	635	277	
2	1060			303	151	645	266	
2	1080			299	149	655	255	
2	1100			295	147	665	244	
2	1120			291	145	675	233	
2	1140			287	143	685	222	
2	1160			283	141	695	211	
2	1180			279	139	705	200	
2	1200			275	137	715	189	
2	1220			271	135	725	178	
2	1240			267	133	735	167	
2	1260			263	131	745	156	
2	1280			259	129	755	145	
2	1300			255	127	765	134	
2	1320			251	125	775	123	
2	1340			247	123	785	112	
2	1360			243	121	795	101	
2	1380			239	119	805	90	
2	1400			235	117	815	79	
2	1420			231	115	825	68	
2	1440			227	113	835	57	
2	1460			223	111	845	46	
2	1480			219	109	855	35	
2	1500			215	107	865	24	
2	1520			211	105	875	13	
2	1540			207	103	885	2	
2	1560			203	101	895		
2	1580			199	99	905		
2	1600			195	97	915		
2	1620			191	95	925		
2	1640			187	93	935		
2	1660			183	91	945		
2	1680			179	89	955		
2	1700			175	87	965		
2	1720			171	85	975		
2	1740			167	83	985		
2	1760			163	81	995		
2	1780			159	79	1005		
2	1800			155	77	1015		
2	1820			151	75	1025		
2	1840			147	73	1035		
2	1860			143	71	1045		
2	1880			139	69	1055		
2	1900			135	67	1065		
2	1920			131	65	1075		
2	1940			127	63	1085		
2	1960			123	61	1095		
2	1980			119	59	1105		
2	2000			115	57	1115		
2	2020			111	55	1125		
2	2040			107	53	1135		
2	2060			103	51	1145		
2	2080			99	49	1155		
2	2100			95	47	1165		
2	2120			91	45	1175		
2	2140			87	43	1185		
2	2160			83	41	1195		
2	2180			79	39	1205		
2	2200			75	37	1215		
2	2220			71	35	1225		
2	2240			67	33	1235		
2	2260			63	31	1245		
2	2280			59	29	1255		
2	2300			55	27	1265		
2	2320			51	25	1275		
2	2340			47	23	1285		
2	2360			43	21	1295		
2	2380			39	19	1305		
2	2400			35	17	1315		
2	2420			31	15	1325		
2	2440			27	13	1335		
2	2460			23	11	1345		
2	2480			19	9	1355		
2	2500			15	7	1365		
2	2520			11	5	1375		
2	2540			7	3	1385		
2	2560			3	1	1395		
2	2580					1405		
2	2600					1415		
2	2620					1425		
2	2640					1435		
2	2660					1445		
2	2680					1455		
2	2700					1465		
2	2720					1475		
2	2740					1485		
2	2760					1495		
2	2780					1505		
2	2800					1515		
2	2820					1525		
2	2840					1535		
2	2860					1545		
2	2880					1555		
2	2900					1565		
2	2920					1575		
2	2940					1585		
2	2960					1595		
2	2980					1605		
2	3000					1615		
2	3020					1625		
2	3040					1635		
2	3060					1645		
2	3080					1655		
2	3100					1665		
2	3120					1675		
2	3140					1685		
2	3160					1695		
2	3180					1705		
2	3200					1715		
2	3220					1725		
2	3240					1735		
2	3260					1745		
2	3280					1755		
2	3300					1765		
2	3320					1775		
2	3340					1785		
2	3360					1795		
2	3380					1805		
2	3400					1815		
2	3420					1825		
2	3440					1835		
2	3460					1845		
2	3480					1855		
2	3500					1865		
2	3520					1875		
2	3540					1885		
2	3560					1895		
2	3580					1905		
2	3600					1915		
2	3620					1925		
2	3640					1935		
2	3660					1945		
2	3680					1955		
2	3700					1965		
2	3720					1975		
2	3740					1985		
2	3760					1995		
2	3780					2005		
2	3800					2015		
2	3820					2025		
2	3840					2035		
2	3860					2045		
2	3880					2055		
2	3900					2065		
2	3920					2075		
2	3940					2085		
2	3960					2095		
2	3980					2105		
2	4000					2115		
2	4020					2125		
2	4040					2135		
2	4060					2145		
2	4080					2155		

[illegible]

TABLE 6

The moments of this function are

$$\begin{aligned} E(\underline{x}) &= \alpha/\beta \\ V(\underline{x}) = \sigma^2(\underline{x}) &= \frac{\alpha}{\beta} \left(1 - \frac{\alpha}{\beta}\right) \frac{1}{\beta+1} \end{aligned} \quad (74)$$

Unfortunately, even this usually "conjugate prior" form does not allow a closed form solution of the projection problem, as exemplified in equations (55) and (56). This is not to say that specific projections cannot be made -- the associated numerical integrations are straightforward, but have not been attempted here.

The more interesting inferential problem may be easily evaluated, however, and is illustrated in Tables 8 through 12.

The data vector is assumed to be

$$\vec{x} = (0, 1, 0, 1, 0, 1, 0, 1, 1, 1, 0, 1, 1, 1, 0, 1, 1, 1, 0, 1, 1, 1, 0)$$

where a "0" represents a failure, a "1" represents a success. Again, this "observed" data vector has been pre-selected to simulate an overly typical result that might appear if $u = .5$ $v = .25$ and repair took place on the 7th trial (the 4th failure). Numerical results now simply require a set of prior parameters and the determination of the first and second moments of equations (61), (62) and (63).

In the calculation of a number of cases for various values of prior parameters, it becomes convenient to work with the success probabilities $1-u$ and $1-v$, rather than u and v directly. Table 7 shows the selection of values of the prior parameters for $1-u$ and $1-v$, and for the repair probability a .

Table	$E(1-u)$	$\sigma(1-u)$	$E(1-v)$	$\sigma(1-v)$	a
8	.5	.2887	.75	.3660	.25
9	.5	.3536	.75	.3953	.25
10	.4	.2619	.6	.4	.25
11	.5	.3536	.75	.3953	.125
12	.5	.3536	.75	.3953	.5

TABLE 7

Prior Parameters Used in Calculation of Tables 8-12

5. MANY FAILURE MODES

5.1 NOTATIONAL EXTENSION

In order to treat the more realistic case of systems with multiple failure modes, we introduce a simple extended model and notation, and then show that this case is solved formally by a simple extension of previously obtained solutions. The development will be only for the continuous model, although a similar one for the discrete case can be directly obtained by means of a parallel analysis.

We now assume that a system can exhibit a total of M independent failure modes (characterized, by definition, by their distinguishability). We also assume that a repair of a mode is possible only at a repair attempt made after an observed failure of that mode.

We then define, for mode i ($i = 1, 2, \dots, M$),

TRIAL NO.	CLP SUCCESS	E(1-u)	$\sigma(1-u)$	E(1-v)	$\sigma(1-v)$	P(R _N)	E(p)	$\sigma(p)$
1	0	.5000	.2887	.7500	.3660	.2500	.4951	.2314
2	1	.3326	.2533	.7500	.3660	.2500	.4951	.2314
3	1	.4055	.2114	.6591	.3101	.2286	.4655	.2058
4	2	.4748	.1932	.6244	.2967	.2364	.4855	.2203
5	2	.4208	.1932	.7083	.3551	.2676	.5089	.2415
6	3	.4334	.1864	.6573	.3465	.2722	.5089	.2415
7	3	.4661	.1854	.6852	.3265	.3321	.5715	.2675
8	4	.4501	.1957	.7036	.3197	.3814	.5945	.2895
9	5	.5066	.1937	.7185	.2997	.4149	.5945	.2895
10	6	.4772	.2040	.6850	.2865	.4535	.5715	.2675
11	6	.4897	.2081	.7151	.2865	.4840	.5945	.2895
12	7	.4577	.2081	.6850	.2865	.5177	.6062	.3033
13	7	.4925	.2149	.7288	.2645	.5685	.6062	.3033
14	8	.4844	.2177	.6979	.2545	.5935	.6150	.3100
15	9	.4520	.2177	.7199	.2455	.6186	.6430	.3304
16	10	.4854	.2149	.7037	.2315	.6430	.6430	.3304
17	11	.4771	.2249	.7037	.2315	.6734	.6235	.3500
18	11	.4781	.2185	.7157	.2233	.6941	.6430	.3304
19	12	.4773	.2241	.7278	.2156	.7141	.6645	.3477
20	13	.4679	.2241	.7092	.2084	.7332	.6645	.3477
21	14	.4776	.2158	.7092	.2084	.7517	.6645	.3477
22	15	.4676	.2158	.7092	.2084	.7517	.6645	.3477

TABLE 8

TRIAL NO.	CLIP SUCCESS	E(1-u)	$\sigma(1-u)$	E(1-v)	$\sigma(1-v)$	P(R _N)	E(p)	$\sigma(p)$
1	0	.5000	.3536	.7500	.3553	.2500	.3750	.3644
2	1	.2750	.2750	.5000	.2953	.5000	.4385	.3058
3	1	.2750	.2750	.5000	.2953	.2500	.4385	.3058
4	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
5	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
6	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
7	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
8	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
9	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
10	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
11	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
12	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
13	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
14	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
15	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
16	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
17	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
18	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
19	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
20	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
21	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
22	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780
23	1	.4000	.2000	.6000	.3861	.2500	.4625	.2780

TABLE 9

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TRIAL NO.	CLIP SUCCESS	E(1-u)	$\sigma(1-u)$	E(1-v)	$\sigma(1-v)$	$P(R_N)$	E(p)	$\sigma(p)$
1	0	.4000	.2619	.6000	.4000	.2500	.3643	.3333
2	1	.2857	.2261	.7143	.4000	.2500	.5148	.0938
3	2	.3650	.2051	.6350	.3897	.3116	.4740	.1333
4	3	.4212	.1851	.5788	.3559	.3301	.4407	.1667
5	4	.4545	.1663	.5455	.3347	.3423	.4597	.1905
6	5	.4746	.1522	.5254	.3186	.3545	.4741	.2000
7	6	.4847	.1422	.5153	.3053	.3657	.4841	.2000
8	7	.4907	.1360	.5093	.2933	.3750	.4941	.2000
9	8	.4943	.1300	.5057	.2846	.3827	.5029	.2000
10	9	.4969	.1250	.5031	.2773	.3883	.5099	.2000
11	10	.4983	.1207	.5017	.2715	.3921	.5174	.2000
12	11	.4987	.1171	.5013	.2663	.3951	.5259	.2000
13	12	.4989	.1141	.5011	.2619	.3971	.5349	.2000
14	13	.4990	.1116	.5010	.2580	.3985	.5434	.2000
15	14	.4991	.1098	.5009	.2549	.3995	.5514	.2000
16	15	.4991	.1083	.5008	.2524	.3999	.5589	.2000
17	16	.4991	.1070	.5007	.2504	.4000	.5664	.2000
18	17	.4991	.1059	.5006	.2489	.4000	.5739	.2000
19	18	.4991	.1049	.5005	.2475	.4000	.5814	.2000
20	19	.4991	.1040	.5004	.2463	.4000	.5889	.2000
21	20	.4991	.1032	.5003	.2451	.4000	.5964	.2000
22	21	.4991	.1025	.5002	.2441	.4000	.6039	.2000
23	22	.4991	.1018	.5001	.2432	.4000	.6114	.2000
24	23	.4991	.1012	.5000	.2424	.4000	.6189	.2000
25	24	.4991	.1006	.5000	.2417	.4000	.6264	.2000
26	25	.4991	.1001	.5000	.2411	.4000	.6339	.2000
27	26	.4991	.0996	.5000	.2406	.4000	.6414	.2000
28	27	.4991	.0991	.5000	.2401	.4000	.6489	.2000
29	28	.4991	.0986	.5000	.2397	.4000	.6564	.2000
30	29	.4991	.0981	.5000	.2393	.4000	.6639	.2000
31	30	.4991	.0976	.5000	.2389	.4000	.6714	.2000
32	31	.4991	.0972	.5000	.2385	.4000	.6789	.2000
33	32	.4991	.0968	.5000	.2381	.4000	.6864	.2000
34	33	.4991	.0964	.5000	.2377	.4000	.6939	.2000
35	34	.4991	.0960	.5000	.2373	.4000	.7014	.2000
36	35	.4991	.0956	.5000	.2369	.4000	.7089	.2000
37	36	.4991	.0952	.5000	.2365	.4000	.7164	.2000
38	37	.4991	.0948	.5000	.2361	.4000	.7239	.2000
39	38	.4991	.0944	.5000	.2357	.4000	.7314	.2000
40	39	.4991	.0940	.5000	.2353	.4000	.7389	.2000
41	40	.4991	.0936	.5000	.2349	.4000	.7464	.2000
42	41	.4991	.0932	.5000	.2345	.4000	.7539	.2000
43	42	.4991	.0928	.5000	.2341	.4000	.7614	.2000
44	43	.4991	.0924	.5000	.2337	.4000	.7689	.2000
45	44	.4991	.0920	.5000	.2333	.4000	.7764	.2000
46	45	.4991	.0916	.5000	.2329	.4000	.7839	.2000
47	46	.4991	.0912	.5000	.2325	.4000	.7914	.2000
48	47	.4991	.0908	.5000	.2321	.4000	.7989	.2000
49	48	.4991	.0904	.5000	.2317	.4000	.8064	.2000
50	49	.4991	.0900	.5000	.2313	.4000	.8139	.2000
51	50	.4991	.0896	.5000	.2309	.4000	.8214	.2000
52	51	.4991	.0892	.5000	.2305	.4000	.8289	.2000
53	52	.4991	.0888	.5000	.2301	.4000	.8364	.2000
54	53	.4991	.0884	.5000	.2297	.4000	.8439	.2000
55	54	.4991	.0880	.5000	.2293	.4000	.8514	.2000
56	55	.4991	.0876	.5000	.2289	.4000	.8589	.2000
57	56	.4991	.0872	.5000	.2285	.4000	.8664	.2000
58	57	.4991	.0868	.5000	.2281	.4000	.8739	.2000
59	58	.4991	.0864	.5000	.2277	.4000	.8814	.2000
60	59	.4991	.0860	.5000	.2273	.4000	.8889	.2000
61	60	.4991	.0856	.5000	.2269	.4000	.8964	.2000
62	61	.4991	.0852	.5000	.2265	.4000	.9039	.2000
63	62	.4991	.0848	.5000	.2261	.4000	.9114	.2000
64	63	.4991	.0844	.5000	.2257	.4000	.9189	.2000
65	64	.4991	.0840	.5000	.2253	.4000	.9264	.2000
66	65	.4991	.0836	.5000	.2249	.4000	.9339	.2000
67	66	.4991	.0832	.5000	.2245	.4000	.9414	.2000
68	67	.4991	.0828	.5000	.2241	.4000	.9489	.2000
69	68	.4991	.0824	.5000	.2237	.4000	.9564	.2000
70	69	.4991	.0820	.5000	.2233	.4000	.9639	.2000
71	70	.4991	.0816	.5000	.2229	.4000	.9714	.2000
72	71	.4991	.0812	.5000	.2225	.4000	.9789	.2000
73	72	.4991	.0808	.5000	.2221	.4000	.9864	.2000
74	73	.4991	.0804	.5000	.2217	.4000	.9939	.2000
75	74	.4991	.0800	.5000	.2213	.4000	.1000	.2000

TABLE 10

TRIAL AC.	CLM. SUCCESS	E(1-u)	$\sigma(1-u)$	E(1-v)	$\sigma(1-v)$	P(R _N)	E(p)	$\sigma(p)$
1	0	.5000	.3536	.7500	.3553	.1250	.1250	.3188
2	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
3	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
4	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
5	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
6	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
7	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
8	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
9	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
10	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
11	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
12	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
13	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
14	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
15	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
16	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
17	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
18	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
19	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
20	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
21	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
22	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188
23	1	.4250	.2500	.7500	.3553	.1250	.1250	.3188

TABLE 11

TRIAL NO.	CLM SUCCESS	E(1-u)	$\sigma(1-u)$	E(1-v)	$\sigma(1-v)$	P(R _N)	E(p)	$\sigma(p)$
1	0	.5000	.3536	.7500	.3553	.5000	.0800	.1409
2	1	.3750	.2500	.5000	.3553	.5000	.0750	.1354
3	1	.3125	.2500	.4375	.3553	.5000	.0700	.1309
4	1	.2500	.2500	.3750	.3553	.5000	.0650	.1264
5	1	.1875	.2500	.3125	.3553	.5000	.0600	.1219
6	1	.1250	.2500	.2500	.3553	.5000	.0550	.1174
7	1	.0625	.2500	.1875	.3553	.5000	.0500	.1129
8	1	.0000	.2500	.1250	.3553	.5000	.0450	.1084
9	1	.0000	.2500	.0625	.3553	.5000	.0400	.1039
10	1	.0000	.2500	.0000	.3553	.5000	.0350	.0994
11	1	.0000	.2500	.0000	.3553	.5000	.0300	.0949
12	1	.0000	.2500	.0000	.3553	.5000	.0250	.0904
13	1	.0000	.2500	.0000	.3553	.5000	.0200	.0859
14	1	.0000	.2500	.0000	.3553	.5000	.0150	.0814
15	1	.0000	.2500	.0000	.3553	.5000	.0100	.0769
16	1	.0000	.2500	.0000	.3553	.5000	.0050	.0724
17	1	.0000	.2500	.0000	.3553	.5000	.0000	.0679
18	1	.0000	.2500	.0000	.3553	.5000	.0000	.0634
19	1	.0000	.2500	.0000	.3553	.5000	.0000	.0589
20	1	.0000	.2500	.0000	.3553	.5000	.0000	.0544
21	1	.0000	.2500	.0000	.3553	.5000	.0000	.0499
22	1	.0000	.2500	.0000	.3553	.5000	.0000	.0454
23	1	.0000	.2500	.0000	.3553	.5000	.0000	.0409

TABLE 12

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λ_i = failure rate when i^{th} mode is unrepaired

μ_i = failure rate when i^{th} mode is repaired

a_i = probability of repairing the i^{th} mode given an attempt is made

The entire system will have an overall failure rate r , which, by virtue of the exponential failure behavior of each component, is

$$r = \sum_{i=1}^M r_i$$

where

$$r_i = \begin{cases} \lambda_i & i^{\text{th}} \text{ mode is unrepaired} \\ \mu_i & i^{\text{th}} \text{ mode is repaired} \end{cases}$$

This last expression serves to recall that, according to our previous analysis, the failure rates are in themselves random variables.

If, then, the failure rate for each mode is a random variable \underline{r}_i , with known p.d.f. $f_{\underline{r}_i}(r_i)$ [and thus known moments], we have in particular for the overall system

$$f_{\underline{r}}(r) = f_{\underline{r}_1}(r_1) * f_{\underline{r}_2}(r_2) * \dots * f_{\underline{r}_M}(r_M) \quad (75)$$

where the $*$ indicates the convolution operation.

Because of the independence of the failure modes, and since the repair of any one mode is independent of the state of the others, we see that each of the $f_{\underline{r}_i}(r_i)$ of equation (75) is available from expressions such as (31) [for projection] or (40) [for inference]. In these expressions we must only

replace the parameters (r, λ, μ, a) by $(r_1, \lambda_1, \mu_1, a_1)$, and note that \bar{t} now represents the times of occurrences of i^{th} mode failures.

To make matters even simpler for practical purposes, we note that since $\underline{r} = \sum \underline{r}_1$, and the \underline{r}_1 are independent, we can immediately write for the expectation and variances:

$$E(\underline{r}) = \sum_{i=1}^M E(\underline{r}_1)$$

$$V(\underline{r}) = \sigma^2(\underline{r}) = \sum_{i=1}^M \sigma^2(\underline{r}_1)$$

6. CONCLUSION

6.1 OTHER MODELS OF RELIABILITY GROWTH

Discussion of the literature on reliability growth models has been intentionally postponed to this final section in order to facilitate comparison with this paper.

The subject of reliability improvement by means of conscious efforts on the part of designers, test engineers, customers, etc. has been of interest from the beginnings of reliability analysis. The modelling of such growth processes has followed, for the most part, a common procedure: formulae are presented that are intended to represent the growth of reliability (or the decrease in failure rate, etc.) as a function of time. These formulae contain unknown parameters, and it becomes a statistical problem to find appropriate estimates (and confidence statements) for these parameters as a

function of observed failure data. Such methods are found, for example, in references [10], [3], [15] and [8]. Sherman [14], for example, finds Maximum Likelihood Estimates for the repair probability a and the unpaired failure probability u when it is assumed that the repaired failure probability v is zero.

Another approach is to assume that little is known about the underlying failure behavior of the system, and what amounts to "almost" non-parametric analysis is made upon eventual failure rates (or probabilities). This is summarized in [1].

Bayesian techniques have been used only recently. A non-parametric Bayesian analysis of a failure probability, constrained to be only non-increasing in time, may be modelled by the technique shown in Samuels [13]. Larson [9] has extended an earlier analysis [8] to produce Bayesian estimates of parameters of a growth model, using prior distributions suggested by Earnest [5]. Finally, Cozzolino [4] has presented a Bayesian approach to a general class of growth models with regard to making minimum-cost decisions about length of tests and burn-in procedures.

All of the above analyses, however, start with a basic assumption: that the reliability will grow (or, at least, will not decrease) in time. If the techniques derived previously were to be used for a system that was actually deteriorating (naturally, or because of well-intentioned intervention), the results would be meaningless. In practice, unfortunately, there is often

a need to have an inferential technique that would spot such deterioration, as well as one equally good at determining appropriate growth characteristics.

6.2 CONCLUSION

This paper has attempted to model a process that simply considers a system (with regard to each failure mode) to be in either a repaired or unrepaired state. The failure rates in each state are known to any desired degree of confidence, and accumulation of failure data serves, in a natural way, to update the knowledge of these state parameters. The observation of failure data also determines the probability that the system is repaired (with respect to each mode).

The weakest points of the model seem to be the assumptions that

- . The repair probability a is known
- . Repair attempts occur only after the observation of a failure

The first point can be overcome (at the expense of additional complexity) by considering a to be a random variable \underline{a} with appropriate prior p.d.f. $f_{\underline{a}}(a|H)$. All analysis would then include a posterior inferential p.d.f. for \underline{a} , given a data vector.

The second point is unfortunately too much at the heart of the model. For many realistic systems, the assumption seems to be valid, however, as the tendency is not to "ruin a good thing".

It should be pointed out that the model considered here is a specific example of a process which Howard [6] calls "Dynamic Inference". This general concept is quite useful in modelling a stochastic process in which the underlying parameters are allowed to change according to yet another stochastic process. The interested reader is referred to reference [6], where (as becomes apparent upon studying the Tables 2-6 and 8-12) the statement is made, "The numerical results indicate a complexity of behavior that challenges intuition".

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